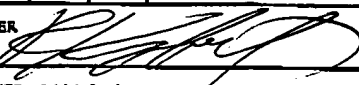



Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-2379		SERIAL NO. 10632,273	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT WALTER M. FARMER et al.			
				FILING DATE July 31, 2000		GROUP 2859 <b>2859</b>	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<b>PK</b>	<del>AA</del> <b>5580821</b>	12/03/96	Alzmine	<del>216</del> <b>216</b>	<del>2</del> <b>2</b>		
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AM							
AN							
AO							
AP							
AQ							
OTHER REFERENCES (including Author, Title, Date, Page(s), Etc.)							
AR							
AS							
AT							
EXAMINER 			DATE CONSIDERED <b>8-24-04</b>				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2379		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Warren M. Farnworth et al.			
					FILING DATE Filed Herewith		GROUP N/A <b>2829</b>	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<i>RK</i>	AA	3,412,456	11/68	Ebisawa				
<i>RK</i>	AB	3,469,019	9/69	Reinmann				
<i>RK</i>	AC	4,105,970	8/78	Katz				
<i>RK</i>	AD	4,141,055	2/79	Berry et al.				
<i>RK</i>	AE	4,182,781	1/80	Hooper et al.				
<i>RK</i>	AF	4,189,825	2/80	Robillard et al.				
<i>RK</i>	AG	4,312,117	1/82	Robillard et al.				
<i>RK</i>	AH	4,315,984	2/82	Okazaki et al.				
<i>RK</i>	AI	4,417,206	11/83	Stowers				
<i>RK</i>	AJ	4,499,656	2/85	Fabian et al.				
<i>RK</i>	AK	4,585,991	4/86	Reid et al.				
<i>RK</i>	AL	4,881,118	11/89	Niwayama et al.				
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
<i>RK</i>	AM 53171	03/91	Japan					
<i>RK</i>	AN 108350	05/91	Japan					
<i>RK</i>	AO 329314	08/89	European (EPO)					
<i>RK</i>	AP <del>6744030</del> 57143838	09/82	Japan					
<i>RK</i>	AQ 2-5540	01/90	Japan					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>RK</i>	AR	Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991						
		Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989						
	AS							
	AT							
EXAMINER <i>RK</i>				DATE CONSIDERED <b>8-24-04</b>				
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					FILING DATE Filed Herewith		GROUP N/A <b>2829</b>	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RL</i>	AU	4,924,589	5/90	Leedy				
<i>RL</i>	AV	4,929,999	5/90	Hoebrechts et al.				
<i>RL</i>	AW	4,937,653	6/90	Blonder et al.				
<i>RL</i>	AX	4,952,272	8/90	Okino et al.				
<i>RL</i>	AY	4,963,225	10/90	Lehman-Lemar				
<i>RL</i>	AZ	5,420,520	5/95	Anschel et al.				
<i>RL</i>	BA	5,014,161	5/91	Lee et al.				
<i>RL</i>	BB	5,032,541	7/91	Sakamoto et al.				
<i>RL</i>	BC	5,045,780	9/91	Swart				
<i>RL</i>	BD	5,072,116	12/91	Kawade et al.				
<i>RL</i>	BE	5,103,557	4/92	Leedy				
<i>RL</i>	BF	5,137,461	8/92	Bindra et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>RL</i>	BG	2232946	09/90	Japan				
<i>RL</i>	BH	410446	01/92	Japan				
	BI							
	BJ							
	BK							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	BL							
	BM							
	BN							
EXAMINER <i>R. J. [Signature]</i>				DATE CONSIDERED <b>8-24-04</b>				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.				
				FILING DATE Filed Herewith	GROUP TWA 2829			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RL	BO	5,177,438	1/93	Littlebury et al.	7	7		
RL	BP	5,177,439	1/93	Liu et al.				
RL	BQ	5,196,251	3/93	Bakhru et al.				
RL	BR	5,206,585	4/93	Chang et al.				
RL	BS	5,235,140	8/93	Reele et al.				
RL	BT	5,239,260	8/93	Widder et al.				
RL	BU	5,245,135	9/93	Schreiber et al.				
RL	BV	5,262,718	11/93	Svendsen et al.				
RL	BW	5,307,561	5/94	Feigenbaum et al.				
RL	BX	5,323,035	6/97	Leedy				
RL	BY	5,326,428	7/94	Farnworth et al.				
RL	BZ	5,334,804	8/94	Love et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CA							
	CB							
	CC							
	CD							
	CE							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	CF							
	CG							
	CH							
EXAMINER 				DATE CONSIDERED 8-24-04				
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					FILING DATE Filed Herewith		GROUP N/A <b>2829</b>	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RK</i>	CI	5,353,195	10/94	Fillion et al.				
<i>RK</i>	CJ	5,367,253	11/94	Wood et al.				
<i>RK</i>	CK	5,402,077	03/95	Agabdel et al.				
<i>RK</i>	CL	5,419,807	05/95	Akram et al.				
<i>RK</i>	CM	5,431,328	07/95	Chang et al.				
<i>RK</i>	CN	5,478,779	12/95	Akram				
<i>RK</i>	CO	5,468,917	11/95	Brodsky et al.				
<i>RK</i>	CP	5,471,151	11/95	DiFrancesco				
<i>RK</i>	CQ	5,477,087	12/95	Kwakita et al.				
<i>RK</i>	CR	5,523,697	06/96	Farnworth et al.				
<i>RK</i>	CS	5,541,525	07/96	Wood et al.				
<i>RK</i>	CT	5,559,444	09/93	Farnworth et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CU							
	CV							
	CW							
	CX							
	CY							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	CZ							
	DA							
	DB							
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